SENTECH Thin Film Metrology Workshop

Thin Film Metrology Workshop – Day 1

Date:	**14 October 2026**
Host:	**SENTECH Gesellschaft für Sensortechnik mbH** Konrad-Zuse-Bogen 13, 82152 Krailling
Location:	**SENTECH Instruments GmbH** **Entrance**: Johann-Hittorf-Str./James-Franck-Str., 12489 Berlin-Adlershof
Networking dinner:	**Restaurant IL Porto**, Semmelweisstraße 104a, 12524 Berlin
Please note:	***Your own laptop will be required for this workshop. Please ensure to bring one with you! A special license for the SpectraRay/4 software will be provided by SENTECH Instruments for the duration of the workshop.***

WORKSHOP PROGRAM:

Pos.	**Time**	**Talk**
1.	9:00	**Welcome to SENTECH Instruments GmbH** Friedrich P. Witek, SENTECH GmbH, Krailling and SENTECH Instruments GmbH, Berlin
2.	9:15	**Introduction to Spectroscopic Ellipsometry** Dr. Raphael Präg, SENTECH Instruments GmbH, Berlin
3.	9:45	**Ellipsometric Workflow and Operation of SpectraRay/4** Dr. Elena Ermilova, SENTECH Instruments GmbH, Berlin
	10:20	***Coffee Break***
4.	10:50	**Understanding Material Dispersion in Ellipsometry** Sven Peters, SENTECH Instruments GmbH, Berlin
	12:00	***Lunch Break / Installation of the Software***
5.	13:20	**Exercise: Iterative Model Improvement**
	15:00	***Coffee Break***
6.	15:30	**Exercise: Advanced Optical Modeling**
7.	17:20	**Automating Ellipsometry: Scripting for Smarter Measurements** Uwe Richter, SENTECH Instruments GmbH, Berlin
	18:20	**End of Workshop – Day 1**
	19:00	**Networking dinner at Restaurant IL Porto**

Thin Film Metrology Workshop – Day 2

Date: **15 October 2026**

Host: **SENTECH Gesellschaft für Sensortechnik mbH**
Konrad-Zuse-Bogen 13, 82152 Krailling

Location: **SENTECH Instruments GmbH**
Entrance: Johann-Hittorf-Str./James-Franck-Str., 12489 Berlin-Adlershof

Please take care not to bring confidential samples or samples under NDA to the Workshop, as these measurements are performed in groups.

On this day, participants will be divided into two groups. Each group will work in the Metrology Application Lab, while the other half will work in Sessions. Group 1 and Group 2 will then switch activities. Please see below for the start times for each group.

WORKSHOP PROGRAM:

Pos.	Time	Event	
1.	9:00	**Welcome to Day 2 of the Workshop** Alexander Treffer, SENTECH Instruments GmbH, Berlin	
2.	9:10	**Ellipsometry of Samples with Non-Idealities, including Backside Reflections causing Depolarization** Dr. Elena Ermilova, SENTECH Instruments GmbH, Berlin	
	9:40	***Coffee Break***	
3.	10:05	**Anisotropic Material Systems** Sven Peters, SENTECH Instruments GmbH, Berlin	
4.	10:30	***Group 1 Practical Workshop –*** **Live Measurement of Customer Samples** Sven Peters	***Group 2 Exercise*:** **Non-Idealities** Dr. Elena Ermilova
	12:15	***Lunch Break***	
5.	13:30	***Group 1 Practical Workshop –*** **Live Measurement of Customer Samples** Sven Peters	***Group 2 Exercise*:** **Anisotropic Materials** Dr. Elena Ermilova
	14:40	***Short Break***	
6.	14:45	***Group 2 Practical Workshop –*** **Live Measurement of Customer Samples** Sven Peters	***Group 1 Exercise*:** **Non-Idealities** Dr. Elena Ermilova
	16:30	***Coffee Break***	
7.	17:00	***Group 2 Practical Workshop –*** **Live Measurement of Customer Samples** Sven Peters	***Group 1 Exercise*:** **Anisotropic Materials** Dr. Elena Ermilova
	18:10	**End of Workshop – Day 2**	